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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete if Known

Application Number	09/535,015
Filing Date	March 24, 2000
First Named Inventor	Shunpei YAMAZAKI et al.
Group Art Unit	2811
Examiner Name	S. Crane
Attorney Docket Number	0756-2131

Sheet	1	of	1
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U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

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SW L		Specification, claims, abstract of Application Serial No. 09/699,466 filed 10/31/2000 to Yamazaki et al.	

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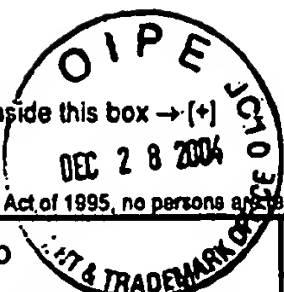
Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
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Examiner Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
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		Office ³	Number ⁴	Kind Code ⁵ (if known)			
SWC		JP	08-045839			02/16/1996	Abst.
		JP	08-045840			02/16/1996	Abst.
SWC		JP	08-097169			04/12/1996	Abst.

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Applicants: Shupey YAMAZAKI et al.

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SWL	6,005,648	12/21/1999	Zhang et al.			
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SWL	0 178 447	10/09/1984	EP			Engl.	
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete If Known

Application Number	09/535,015
Filing Date	March 24, 2000
First Named Inventor	Shunpei YAMAZAKI et al.
Group Art Unit	2811
Examiner Name	S. Crane
Attorney Docket Number	0756-2131

Sheet

1

of

2

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
SWC		5,940,690		Kusumoto et al.	08/17/1999	
		6,337,232		Kusumoto et al.	01/08/2002	
		6,541,795		Kusumoto et al.	04/01/2003	
		5,888,857		Zhang et al.	03/30/1999	
		6,323,071		Zhang et al.	11/27/2001	
		6,338,991		Zhang et al.	01/15/2002	
		6,413,805		Zhang et al.	07/02/2002	
		6,071,764		Zhang et al.	06/06/2000	
		6,077,758		Zhang et al.	06/20/2000	
		6,455,401		Zhang et al.	09/24/2002	
		2002/0025659		Yamazaki et al.	02/28/2002	
		2002/0048891		Yamazaki et al.	04/25/2002	
		6,423,586		Yamazaki et al.	07/23/2002	
		6,194,254		Takemura	02/27/2001	
		6,482,686		Takemura	11/19/2002	

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Examiner Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	†
		Office ²	Number ³	Kind Code ⁴ (if known)				
SWC		JP	07-335906			12/22/1995		Abst. & U.S. Equiv.
		JP	07-045519			02/14/1995		Abst. & U.S. Equiv.
		JP	07-231100			08/29/1995		Abst. & U.S. Equiv.
		JP	07-094757			04/07/1995		Abst. & U.S. Equiv.
		JP	07-192998			07/28/1995		Abst.
SWC		JP	05-299339			11/12/1993		Abst. & U.S. Equiv.

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if Known			
				Application Number		09/535,015	
				Filing Date		March 24, 2000	
				First Named Inventor		Shunpei YAMAZAKI et al.	
				Group Art Unit		2811	
				Examiner Name		S. Crane	
Sheet	2	of	2	Attorney Docket Number		0756-2131	

U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
SWL		6,162,704		Yamazaki et al.	12/19/2000	
		6,294,441		Yamazaki	09/25/2001	
		6,461,943		Yamazaki et al.	10/08/2002	
		6,620,711		Yamazaki	09/16/2003	

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Examiner Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Office ³	Number ⁴	Kind Code ⁵ (if known)			
SWL		JP	07-066425			03/10/1995	Abst. & U.S. Equiv.
		JP	08-045839			02/16/1996	Abst. & U.S. Equiv.
		JP	08-045840			02/16/1996	Abst. & U.S. Equiv.
		JP	08-097169			04/12/1996	Abst. & U.S. Equiv.
SWL		KR	96-005879			02/23/1996	U.S. Equiv.

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²

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		Number	Kind Code ² (if known)			
SWC		4,759,610		Yanagisawa	07/26/1988	
SWC		5,535,471		Guldi	07/16/1996	
SWC		5,661,056		Takeuchi	08/26/1997	

FOREIGN PATENT DOCUMENTS								
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SWC		Wolf, <i>Silicon Processing for the VLSI ERA</i> , Volume 2: Process Integration, Page 274 (1990)	

Examiner Signature	CRANE	Date Considered	11/6/03
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

¹ Unique citation designation number. ² Applicant is to place a check mark here if English language Translation is attached.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	09/535,015
				Filing Date	March 24, 2000
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2811
				Examiner Name	S. Crane
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		Number	Kind Code ² (if known)			
SWL		5,306,651		Masumo et al.	04/26/1994	
		5,893,730		Yamazaki et al.	04/13/1999	
		5,932,893		Miyanaga et al.	08/03/1999	
		6,133,073		Yamazaki et al.	10/17/2000	
		6,225,152	B1	Yamazaki et al.	05/01/2001	
		6,288,412	B1	Hamada et al.	09/11/2001	
SWL		6,323,072	B1	Yamazaki et al.	11/27/2001	

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		Office ³	Number ⁴	Kind Code ⁵ (if known)				

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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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				Filing Date	March 24, 2000
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2811
				Examiner Name	S. Crane
Sheet	1	of	1	Attorney Docket Number	0756-2131

U.S. PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
SGC		5,591,988		Arai et al.	01/07/1997	
		5,953,597		Kusumoto et al.	09/14/1999	
		6,011,275		Ohtani et al.	01/04/2000	
SWC		6,331,718		Yamazaki et al.	12/18/2001	

FOREIGN PATENT DOCUMENTS								
Examiner Initials ¹	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Office ³	Number ⁴	Kind Code ⁵ (if known)				
SWC		JP	06-314785		Suzawa et al.	11/8/1994		Abstract
SWC		JP	06-314787		Suzawa et al.	11/8/1994		Abstract

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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Examiner Signature	CRANE	Date Considered	10/18/02
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¹ Unique citation designation number. ² Applicant is to place a check mark here if English language Translation is attached.

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Form PTO 1419 (Rev. 8-83) JAN 04 2002 INFORMATION DISCLOSURE STATEMENT		U.S. Department of Commerce Patent and Trademark Office		Atty Docket 0756-2131		Serial No. 09/535,015	
				Applicants: Shupei YAMAZAKI et al.			
				Filing Date: March 24, 2000		Group Art Unit: 2825	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
SWC	5,728,259	03/17/1998	Suzawa et al.				
Examiner CRANE				Date Considered 10/18/02			
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Form PTO-1449 (Rev. 8-83)		Department of Commerce Patent and Trademark Office		Atty Docket 0756-2001		Serial No. 09/535,015	
INFORMATION DISCLOSURE STATEMENT				Applicants: Shupeí YAMAZAKI et al.			
				Filing Date: March 24, 2000		Group Art Unit: 2825	
8. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
SWC	3,890,632	06/17/1975	Ham et al.				
	4,330,363	05/18/1982	Biegesen et al.				
	4,466,073	08/14/1984	Boyan et al.				
	5,543,636	08/06/1996	Yamazaki				
	5,686,328	11/11/1997	Zhang et al.				
	5,763,899	06/09/1998	Yamazaki et al.				
	5,782,665	07/21/1998	Weisfield et al.				
	5,922,125	07/13/1999	Zhang.H				
	5,929,527	07/27/1999	Yamazaki et al.				
	5,949,107	09/07/1999	Zhang				
	6,031,249	02/29/2000	Yamazaki et al.				
	6,083,801	07/04/2000	Ohtani.H				
	6,121,683	09/19/2000	Yamazaki et al.				
	6,140,165	10/31/2000	Zhang et al.				
	6,147,667	11/14/2000	Yamazaki et al.				
	6,175,348	01/16/2001	Zhang et al.				
	6,180,439	01/30/2001	Yamazaki et al.				
	6,207,969	03/27/2001	Yamazaki				
SWC	6,278,132	08/21/2001	Yamazaki et al.				
FOREIGN PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No	
SWC	07-335900	12/22/1995	JP			Eng Abst	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
Examiner Initial							
SWC	Baker, Jr. et al., "Field Effect Transistor", pp. 849, 1968, IBM Technical Disclosure Bulletin, Vol. 11, No. 7						
Examiner CRANE				Date Considered 7/7/03			
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Applicant: Shunpei YAMAZAKI et al.

Filing Date: March 24, 2000

Group: 2811

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 09/539015
 03/24/00
U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
SWC	5,403,772	04/04/95	Zhang et al			
	5,426,064	06/20/95	Zhang et al			
	5,481,121	01/02/96	Zhang et al			
	5,488,000	01/30/96	Zhang et al			
	5,492,843	02/20/96	Adachi et al			
	5,501,989	03/26/96	Takayama et al			
	5,508,533	04/16/96	Takemura			
	5,529,937	06/25/96	Zhang et al			
	5,534,716	07/09/96	Takemura			
	5,543,352	08/06/96	Ohtani et al			
	5,563,426	10/08/96	Zhang et al			
	5,569,610	10/29/96	Zhang et al			
	5,569,936	10/29/96	Zhang et al			
	5,580,792	12/03/96	Zhang et al			
	5,585,291	12/17/96	Ohtani et al			
SWC	5,589,694	12/31/96	Takayama et al			

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SWC	R.J. Nemanich et al, "Structure and Growth of the Interface of Pd on α -SiH", The American Physical Society - Physical Review, Vol. 22, No. 12, pp. 6828-6831, June 1981
SWC	M.J. Thompson et al, "Silicide Formation in Pd- α -Si:H Schottky Barriers", Appl. Phys. Lett., Vol. 39, No. 3, pp. 274-276, August 1981
SWC	Hayashi et al., "Fabrication of Low-Temperature Bottom-Gate Poly-Si TFTs on Large-Area Substrate by Linear-Beam Excimer Laser Crystallization and Ion Doping Method", IEEE IEDM 1995, pages 829-832.
SWC	R.J. Nemanich et al, "Initial Phase Formation at the Interface of Ni, Pd, or Pt and Si", Mat. Res. Soc. Symp. Proc., Vol. 25, 1984

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SWC	5,595,923	01/21/97	Zhang et al			
	5,595,944	01/21/97	Zhang et al			
	5,604,360	02/18/97	Zhang et al			
	5,605,846	02/25/97	Ohtani et al			
	5,606,179	02/25/97	Yamazaki et al			
	5,608,232	03/04/97	Yamazaki et al			
	5,612,250	03/18/97	Ohtani et al			
	5,614,426	03/25/97	Funada et al			
	5,614,733	03/25/97	Zhang et al			
	5,616,506	04/01/97	Takemura			
	5,620,910	04/15/97	Teramoto			
	5,621,224	04/15/97	Yamazaki et al			
	5,624,851	04/29/97	Takayama et al			
	5,637,515	06/10/97	Takemura			
	5,639,698	06/17/97	Yamazaki et al			
	5,643,826	07/01/97	Ohtani et al			
	5,646,424	07/08/97	Zhang et al			
	5,654,203	08/05/97	Ohtani et al			
	5,656,825	08/12/97	Kusumoto et al			
	5,663,077	09/02/97	Adachi et al			
	5,700,333	12/23/97	Yamazaki et al.			
	5,677,549	10/14/97	Takayama et al.			
	5,696,386	12/9/97	Yamazaki			
	5,696,388	12/9/97	Funada et al.			
SWC	5,705,829	1/6/98	Miyanaga et al.			

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Filing Date March 24, 2000

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SWC	5,712,191	01/27/98	Nakajima et al.			
	5,756,364	05/26/98	Tanaka et al.			
	5,849,611	12/15/98	Yamazaki et al.			
	5,712,191	1/27/98	Nakajima et al.			
	5,744,822	04/28/98	Takayama et al.	257	66	
	5,744,824	04/28/98	Kousai et al.	257	74	
	5,766,977	06/16/98	Yamazaki	438	151	
	5,773,846	06/30/98	Zhang et al.	257	66	
	5,773,847	06/30/98	Hayakawa	257	66	
	5,773,327	06/30/98	Yamazaki et al.	438	154	
	5,795,795	08/18/98	Kousai et al.	437	174	
	5,808,321	09/15/98	Mitanaga et al.	257	72	
	5,811,327	09/22/98	Funai et al.	438	166	
	5,818,076	10/06/98	Zhang et al.			
	5,821,138	10/13/98	Yamazaki et al.	438	166	
SWC	5,824,574	10/20/98	Yamazaki et al.	438	150	

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